USSN 10/789,328 Atty. Docker No. 2003-0107-01

IN THE SPECIFICATION:

Please amend the title on page 1, as follows:

Methods and Apparatus for Improved Bandwidth Estimation Measurement and Bandwidth Parameter Calculation for Laser Light

Please amend the abstract as follows:

A bandwidth meter method and apparatus for measuring the bandwidth of a spectrum of light emitted from a laser input to the bandwidth meter is disclosed, which may comprise an optical bandwidth monitor providing a first output representative of a first parameter which is indicative of the bandwidth of the light emitted from the laser and a second output representative of a second parameter which is indicative of the bandwidth of the light emitted from the laser; and, an actual bandwidth calculation apparatus utilizing the first output and the second output as part of a multivariable equation employing predetermined calibration variables specific to the optical bandwidth monitor, to calculate an actual bandwidth parameter. The notual bandwidth purameter may comprise a spectrum full width at some percent of the maximum within the full width of the spectrum of light omitted from the laser ("FWXM") or a width-between two points on the spectrum-enclosing some percentage of the energy of the full-spectrum of the spectrum of light-omitted-from the laser ("EX"). The bandwidth monitor may comprise un etalon and the first output is representative of at least one of a width of a fringe of an optical output of the staten at FWXM or a width between two points on the spectrum enclosing some percentage of the energy of the full spectrum of light-emitted from the laser ("EX") and the second output is representative of at-least one of a second FWX"M or EX", where X≠X" and X'≠X". The precomputed enlibration variables muy be derived from a measurement of the value of the actual bandwidth parameter utilizing a trusted standard, correlated to the occurrence of the first and second outputs for a calibration spectrum. Tthe value of the notual bundwidth parameter is calculated from the equation: estimated actual BW parameter - K*w, + 1,*w, + M, where w, - the first-measured-output-representative of EWXM or EX' and wa is the second-measured output representative of FWX"M or EX". The apparatus and method may be

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implemented in a laser lithography light source and/or in an integrated circuit lithography tool.